Imaging Science at PAL-XFEL :Visualization of ultrafast phenomena at nanoscale resolution

Daewoong Nam

November 14, 2023





Contents

Introduction: Imaging science programs at PAL-XFEL

Current status of coherent diffraction imaging instrument at PAL-XFEL

* New endstation equipped with K-B mirrors for nanobeams at the hard X-ray beamline

1

***** Summary









(figure) Single-shot coherent X-ray imaging instrument at PAL-XFEL. X-ray free electron laser (XFEL) pulses are focused by Kirkpatrick–Baez mirrors (KB mirrors) with a ~5.96 m long focal length and delivered to the sample chamber. Fresh samples are supplied using a thin membrane to each X-ray pulse in the sample chamber. Diffracted signals from samples are collected by the multiport chargecoupled device (MPCCD). To avoid damage to the sensor, the beam stopper is located just upstream of the detector and blocks the direct X-ray beam. The detector parts marked by the blue box are mounted on the rail to easily change the distance between the sample and detector.

(figure) (a) The overall schematics of the sample chamber. (b) Internal components of the sample chamber. (the XFEL beam propagates following the z-axis in the figure)

D. Sung, D. Nam et al., Appl. Sci. 11, 5082 (2021)



(figure) A Ce:YAG crystal is used to synchronize Xray and a femtosecond optical laser in the fixed target scheme. It enables to synchronize two light sources with femtosecond precision.

(figure) Demonstration of pump-probe imaging. (a) Diffraction pattern of an intact Ag nanosphere. (b) Radial summation of (a). (c) & (d) The measured diffraction patterns with a time delay of 16 ps and 45 ps. 5

We demonstrated a single-shot pump-probe imaging, which can visualize the ultrafast phenomena of the specimens at picosecond temporal and nanometer **spatial resolutions**. In particular, it can be applied to investigate irreversible phenomena in the case of

D. Sung, D. Nam et al., Appl. Sci. 11, 5082 (2021)





D. Nam et al., J. Korean Phys. Soc. 76, 6 (2022)





(figure) Pump-probe multiplex imaging using femtosecond X-ray pulses. A femtosecond IR laser drives the melting process of core-shell nanoparticles and small/wide-angle X-ray diffraction patterns are simultaneously collected while changing the time delay of two light sources. 7

By modifying the CXI chamber's exit port, we could accommodate two JUNGFRAU 0.5M, aimed at collecting Bragg peaks at a fixed

However, the azimuthal coverage of these two detectors remains

While this setup suffices for comprehending the atomic arrangement of polycrystalline samples, its effectiveness is limited when studying single crystal samples due to the random distribution of sample orientations on the thin membrane.

J. Shin et al., Nano Lett. 23, 4 (2023)





2023	User beamtime	Instrument	Remarks
	Pump-probe multiplex experiments	multiplex imaging chamber JUNGFRAU 4M for SAXD JUNGFRAU 5M for WAXD JUNGFRAU 0.5M for XES	A new large area detector for WAXD
	<image/>	(a) (b) (c) (c) (c) (c) (c) (c) (c) (c) (c) (c	a) Diffraction pattern from LaB ₆ powder.
	- Two JUNGFRAU 0.5N	Λ	- JUNGFRAU 5M
	- 2th is fixed, 30°±7°.		-> - 2th range: 18°~ 44°
	- azimuth angle: ~ 38	% covered by two detectors	- Fully covered in azimuth

9



al direction (2th: 33°~ 44°) J. Hwang *et al.*, in preparation

Multiplex imaging chamber

Multiplexing experiment

- Investigation using complementary X-ray techniques for comprehensive understanding of the ultrafast phenomena.



(figure) A photograph of the multiplex imaging chamber and two detectors to collect small/wide-angle X-ray diffraction patterns. The whole instrument is installed on the NCI hutch at hard X-ray beamline, PAL-XFEL.

- Small Angle X-ray Diffraction (SAXD)
- : for obtaining morphological images
- Wide Angle X-ray Diffraction (WAXD)
- : for obtaining the crystal arrangement at the atomic-scale
- X-ray Emission Spectroscopy (XES)
- : for identifying corresponding electronic structure



(figure) 3D schematic showing the interior parts of multiplex imaging chamber. JUNGFRAU 5M for WAXD and JUNGFRAU 0.5 M for XES are mounted. Von-Hamos spectrometer is used to reveal electronic structural information of the specimens.



Multiplex imaging chamber

Commissioning of multiplex imaging experiment

- Photon energy is determined by considering following three factors.
- : the oversampling ratio for the imaging experiment
- : the position of the Bragg peak under the fixed detector geometry
- : the X-ray absorption edge of the target atom.

Simultaneous measurement of three different signals of gold nanoparticles



(figure) (a) The small angle diffraction pattern of a single Au NP. (b) The periodic arrangement of the sample formed strong diffraction peaks on the detector. The observed diffraction peaks were (111) and (200) peaks corresponding to atomic spacings of 2.35 Å and 2.04 Å, respectively. (c) The diffraction intensity as a function of the two theta angles is shown by averaged over the azimuth angle. (b & c) Simultaneous measurements were taken with the same particle measured in (a). (d) Using the von Hamos spectrometer with a Si(444) crystal analyzer, Au L α_1 (9.713 keV) and L α_2 (9.628 keV) spectrum were collected. More than 1000 X-ray pulses were exposed to improve the signal-to-noise ratio (SNR) of emissions. In addition, the bent crystal allowed the X-rays to be focused vertically for better SNR. (e) The L α_1 emission intensity is ~ 10 times higher than the L α_2 emission. The energy resolution from the detector pixel size was 0.68 eV in this von Hamos geometry.

***** New project with photon science center, POSTECH



(figure) A schematic of the NCI hutch in 2020.

- new endstation for studying of functional nanomaterial and biological specimens
- key instrument: nanofocusing optics
- : improve X-ray flux density effectively
- : promote high resolution imaging by increasing in X-ray flux density
- : develop new science programs utilizing nanobeams



Focusing optics: diagnostic part

- Quadrant Beam Position Monitor (QBPM)
- : Thin foils (Si₃N₄ membrane and CVD) and four PDs (backscattering geometry)
- : Provide estimated the beam position and the incident flux without disturbing X-rays

- <u>Slit</u>

- : 2 mm tungsten carbide blades X 4
- : Block the parasitic scattering from upstream optics
- Beam Position Monitor (BPM)
- : Ce:YAG crystal and vision camera
- : Intuitively provide the X-ray position on the crystal but disturb X-rays



(figure) A photograp endstation.

(figure) A photograph of the diagnostic part at the new

***** Focusing optics: K-B mirrors



(figure) A photograph of a new K-B mirrors chamber.



	Horizontal focusing mirror	Vertical focusing mirror	
Surface profile	Elliptical cylinder		
Substrate material	SiO ₂		
Surface coating	Ir 50 nm (6 mm width) and non-coated (7 mm width)		
Mirror substrate size	300 mm x 50 mm x 50 mm (L x W x H)		
Effective mirror area	290 mm x 15 mm		
Grazing incidence angle	6 mrad		
Focal length	910 mm	600 mm	
Spatial acceptance	1.74 mm	1.74 mm	

(table) Specification of new K-B mirrors.

Simulation

Source to mirror distance = 153,125 mm Source size = 0.05 mm-> expected focused beam size (H X V) ~ 300 nm X 200 nm



22nd International Advisory Committee Meeting (November 13-14, 2023)

New endstation equipped K-B mirrors for nanobeam

***** Focusing optics: K-B mirrors

- photon energy: 9.5 keV
- reflection area: Ir
- focused beam size (FWHM): ~ 350 nm X 270 nm (H X V)
- → The focused beam size closely matches the simulation value, 300 nm by 200 nm.



(figure) Focused beam size measurement by wire scan. The beam size is about 350 nm by 270 nm.

Instrument for coherent diffraction imaging

- Diffraction chamber including a slit stage, a mirror stage for microscope and a sample stage is ready.
- Fixed target is available with 60 Hz repetition rate.
- A large area detector, JUNGFRAU 4M, is available.
- Multiplex experiment, SAXD and WAXD, will be available from 2024.



(figure) Imaging instrument installed at the new endstation.



Instrument for coherent diffraction imaging

- Single-shot imaging experiment has been successfully demonstrated at the new endstation.
- Gold nanospheres with 50 nm diameter were dispersed on the Si_3N_4 membrane.
- X-ray energy was set to 5 keV and focused beam size was ~ 500 nm by 650 nm.
- Fs. IR laser pump X-ray probe experiment with sub ps precision is available now.



- Diffraction pattern of gold nanoparticle with 50 nm diameter. А
- Radial summation of the diffraction pattern. The signal extends to ~ 5 nm in spatial resolution. В
- Timing synchronization of two light sources, IR laser and X-rays, with femtosecond precision using a Ce:YAG crystal. С



Summary

Multiplex imaging experiment

- As the result of "Accelerator core technology development project" funded by NRF, the new instrument for multiplexing experiment has been developed.
- This instrument drives to comprehensive understanding of the ultrafast phenomena through three different information.

***** XFEL experiments using nanobeam

- We've successfully constructed the new endstation equipped with K-B mirrors and demonstrated single-shot imaging with nanobeam.
- As the first nanofocusing system using K-B mirrors in Korea, we earned valuable know-how through this project.
- Investment for infra strengthens the capability of PAL staffs.
- 16 beamline scientists form a tie up with user groups to utilize nanobeams and we show the possibility to solve scientific problems using this endstation through internal beamtime.

CDI at the soft X-ray beamline

- As another project with Photon Science Center, we are constructing a new endstation at the soft X-ray beamline.
- Tight focusing system by K-B mirrors is employed for single-shot experiment including coherent diffraction imaging.
- Commissioning of focusing system will be conducted in 2024.
- Because of the budget issues, manufacture of a sample chamber is stopped now.



Thanks to:

PAL-XFEL, PAL

Sangsoo Kim, Sunam Kim, Sang Han Park, Minseok Kim, Intae Eom, Tae-Yeong Koo and all staffs of XFEL beamline department

Photon Science Center, POSTECH

Changyong Song and Jae Hoon Park

Sogang Univ. Hyunjung Kim

RIKEN SPring-8 Center

Makina Yabashi and Tetsuya Ishikawa



